

## ESD TEST REPORT

<b>Field-Induced Charged-Device Model</b>
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<b>JS-002-2018</b>
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ANSI/ESDA/JEDEC Standard, Method JS-002-2018 is an ESD test using Field-Induced Charged-Device Model, three positive and three negative pulses applied to the devices per customer's specification with 0.5 second cool down between pulses.

**Customer :** Chongqing Alpha and Omega Semiconductor Limited

**Address:** No. 288 Yuefu Road, Beibei District, Chongqing, P.R. China

### Device Information

Part No. :	AOCA32317	Sample Size :	3pcs
Package Type :	MCSP3.37x1.47_10	Pin Count :	10
Lot No. :	AAB0118.01 (1101)	Date Code :	-
VDD Domains :	S2 S1	VSS Domains :	S1 S2

### Test Equipment

Tester1 :	ZAPMASTER MK.2 SE	Serial No. :	0508317
Calibration Date :	Jan 14 <sup>th</sup> 2021	Expiration Date :	Jan 13 <sup>th</sup> 2022
Tester2 :	Orion Robotic CDM Test System	Serial No. :	0806294
Calibration Date :	Jan 15 <sup>th</sup> 2021	Expiration Date :	Jan 14 <sup>th</sup> 2022

### Environmental Condition

Temperature :	23°C	Humidity :	30% RH
Submit date :	Feb 2 <sup>nd</sup> 2021	Complete date :	Feb 2 <sup>nd</sup> 2021



### Stress Summary

CDM			
Sample No.	Voltage Level	Process	Spot Test Results* (Within 10 $\mu$ A @ 20V between G and S2/S1)
9#	$\pm 2kV$	All Pins Done	PASS
10#		All Pins Done	PASS
11#		All Pins Done	PASS

### Test Result\*

Model	Pin Combinations	ESD Sensitivity Pass*: <u>2kV</u>	V Class: <u>C3</u>
CDM	ALL PINS DONE	$\pm 2kV$	JS-002-2018 Class C0a: <125V Class C0b: 125V to <250V Class C1: 250 to <500 V Class C2a: 500 to <750 V Class C2b: 750 to <1000 V Class C3: <u><math>\geq 1000V</math></u>

\*Note: Results will be updated based on customer final electrical test results.

Test Engineer: Wenping Yan	Date: Feb 2 <sup>nd</sup> 2021	
Approved by FA Manager: 	Date: Feb 2 <sup>nd</sup> 2021	

### Recommendations

**EAG Shanghai** certifies that above tests have been performed in accordance to the requirements stated above and per the customer purchase order and applicable documents.

**EAG Shanghai** recommends electrical testing as a validation of reported results. Curve Trace criteria was utilized to specify a pass or fail. Industry standards require the device to be tested functionally at post stress and should continue to meet all electrical parameters as per the data sheet.

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